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RCE
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#23103

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 09/778,245 Confirmation No.: 9085
First Named Inventor: SHING LEE ET AL. Filing Date: February 6, 2001
Group Art Unit: 2877 Examiner: Hoa O. Pham
Atty. Docket No.: M-10685-1C US
Title: SYSTEM FOR MEASURING POLARIMETRIC SPECTRUM AND OTHER PROPERTIES OF A SAMPLE
Assignee: KLA-TENCOR CORPORATION

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San Francisco, California
January 22, 2003

BOX RCE
COMMISSIONER FOR PATENTS
Washington, D. C. 20231

REQUEST FOR CONTINUED EXAMINATION (RCE)

Dear Sir:

This is a Request under 37 C.F.R. § 1.114 for Continued Examination of the above-identified application.

Please consider the Supplemental Information Disclosure Statement, which are enclosed/were previously submitted.

The Commissioner is hereby authorized to charge the RCE fee of \$750.00, required under 37 C.F.R. § 1.17(e), to Deposit Account No. 19-2386. The Commissioner is also authorized to charge any other fees which may be required. A duplicate copy of this sheet is attached.

Please contact the undersigned attorney at (415) 217-6000 with any questions concerning this request or the above-identified patent application.

LAW OFFICES OF
SKJERVEN MORRILL LLP
San Jose, CA
San Francisco, CA

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#913569 v1 - M-10685-1C US - RCE application

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Application No. 09/778,245

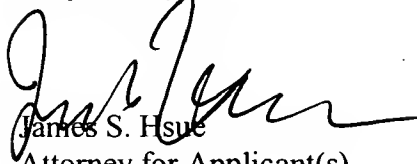
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EXPRESS MAIL LABEL NO:

EV 259161167 US

Respectfully submitted,



James S. Hsue

Attorney for Applicant(s)

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